

**AMENDMENTS TO THE CLAIMS**

1. (Currently Amended) An electronic device testing apparatus for conducting a test by pressing input/output terminals of electronic devices to be tested against ~~contact portions~~ sockets of a test head, wherein:

~~said test~~ the test head has a plurality of ~~contact~~ socket groups each ~~including of~~ which is composed of a set of ~~said contact portions~~ the sockets;

~~said electronic~~ the electronic device testing apparatus ~~comprises~~ comprising:

a plurality of moving ~~means~~ devices each of which is capable of independently moving a strip ~~formats~~ format loaded with ~~said electronic~~ the electronic devices to ~~said contact~~ the socket groups and pressing ~~said electronic~~ the electronic devices against ~~said contact portions~~ the sockets while holding ~~said electronic~~ the electronic devices on ~~said strip~~ the strip format,

wherein the electronic devices are moved together with an entirety of the strip format.

2. (Cancelled)

3. (Currently Amended) An electronic device testing apparatus for conducting a test by pressing input/output terminals of electronic devices to be tested against ~~contact portions~~ sockets of a test head wherein:

~~said test~~ the test head has a plurality of ~~contact~~ socket groups each ~~including of~~ which includes a set of ~~said contact portions~~ the sockets;

~~said electronic~~ the electronic testing apparatus ~~comprises~~ comprising:

a plurality of moving ~~means~~ devices each of which is capable of independently moving a strip ~~formats~~ format loaded with ~~said electronic~~ the electronic devices to ~~said groups~~ the sockets and pressing ~~said electronic~~ the electronic devices against said ~~contact portions~~ the sockets while holding ~~said electronic~~ the electronic devices on ~~said strip~~ formats the strip format; and

a control ~~means~~ device configured to finish ~~for finishing~~ tests with the shortest time on the remaining ~~said electronic~~ electronic devices on ~~said strip~~ the strip format when a lot of ~~said electronic~~ the electronic devices finishes.

4. (Currently Amended) The electronic device testing apparatus as set forth in claim 3, wherein in the case where ~~said the~~ strip format loaded with ~~said the~~ electronic devices is already on ~~said contact~~ the socket group when a lot of ~~said the~~ electronic devices finishes, ~~said the~~ control means device suspends a test on ~~said the~~ electronic devices already under the test in ~~said contact~~ the socket group and outputs an instruction to move ~~said the~~ strip format loaded with ~~said the~~ electronic devices to ~~other contact~~ another socket group already finished ~~with tests with the test~~ and having a large number of sockets ~~contact portions~~.

5. (Currently Amended) The electronic device testing apparatus as set forth in claim 3, wherein ~~said the~~ control means device determines ~~to which contact~~ which socket group ~~said the~~ strip format loaded with the remaining ~~said electronic~~ devices yet to be supplied to

any ~~contact-socket~~ group when a lot of ~~said- the~~ electronic devices finishes should be supplied, based on the number of the electronic devices on ~~said-the~~ strip format, the number of ~~contact-portionssockets~~ in respective ~~contact-socket~~ groups, and standby time until a test.

6. (Currently Amended) The electronic device testing apparatus as set forth in any one of claims 1 and 3 to 5, wherein each of ~~said-the~~ moving ~~means-devices~~ moves by gripping ~~said-the~~ strip format loaded with ~~said-the~~ electronic devices from a loading position of pre-test electronic devices to a corresponding ~~contact-socket~~ group.

7. (Currently Amended) The electronic device testing apparatus as set forth in any one of claims 1 and 3 to 5, wherein each of ~~said-the~~ moving ~~means-devices~~ moves by gripping ~~said-the~~ strip format loaded with ~~said-the~~ electronic devices from ~~said-the~~ corresponding ~~contact-socket~~ group to a loading position of post-test electronic devices.

8. (Currently Amended) The electronic device testing apparatus as set forth in any one of claims 1 and 3 to 5, wherein a sum of the numbers of ~~contact-portionssockets~~ composing ~~said-the~~ plurality of ~~contact-socket~~ groups in ~~said-the~~ test head is  $2^n$  ("n" is a natural number).

9. (Original) The electronic device testing apparatus as set forth in claim 8, wherein  $n=5$ .

10. (Original) The electronic device testing apparatus as set forth in claim 8, wherein  
n=6.

11-17. (Cancelled)

18. (Currently Amended) The electronic device testing apparatus as set forth in claim  
1, wherein the number of ~~contact portions~~sockets which ~~compose~~include at least two ~~contact~~  
~~groups~~ of a plurality of ~~said contact~~the socket groups are mutually different.